FINAL PRODUCT/PROCESS CHANGE NOTIFICATION # 16679

Generic Copy

Issue Date: 13-July-2011

TITLE: Common Mode Filter (EMI4182 and EMI4183) Dual Fab Source

PROPOSED FIRST SHIP DATE: 13-Oct-2011

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Fab Site

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor Sales Office or <Eric.Dominguez@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office

ADDITIONAL RELIABILITY DATA: Available
Contact your local ON Semiconductor Sales Office or <Lakshmi.Kari@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

An additional source for the ESD die will be added to the manufacturing BOM for devices EMI4182 and EMI4183. The additional source is ON Semiconductor's Fab 2 in Oudenaarde (Belgium) Fab 2 is an internal factory that is TS16949 and ISO-14000 certified. This new die is being added to ensure that manufacturing supply of these products are continuous and in the quantity needed to fulfil production orders.

There will be no change to electrical specifications or device physical parameters.

Qualification testing has been completed with zero failures.

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RELIABILITY DATA SUMMARY:

Reliability Test Results:

Test	**Conditions**	**Results**
EMI4182		
High Temp Reverse Bias	Ta=125°C, Bias	504 Hrs 0/80
Highly Accelerated Stress Test (Preconditioned)	Ta=131°C, RH=85%, Pressure = 18.8 PSIG Bias	96 Hrs 0/84
EMI4183		
Autoclave (Preconditioned)	Ta=121°C, H=100% Pressure = 15 PSIG	96 Hrs 0/84
High Temperature Storage Life	Ta=150°C	504 Hrs 0/86
Scanning Acoustic Tomography	Preconditioned MSL1 260°C	0/10
Temperature Cycling (Preconditioned)	-65°C to 150°C	500 Cyc 0/86

ELECTRICAL CHARACTERISTIC SUMMARY:

DC, Capacitance, ESD, RF and Applications testing was performed on qualification samples and compared to the original device qualification. Characterization meets device specifications as listed in the datasheet compares well to the original device data. Characterization results are available for review upon request.

CHANGED PART IDENTIFICATION:

There will be no changes to the standard device markings. Normal assembly lots traceability codes will used to identify the ESD die type.

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List of affected General Parts:

EMI4182MTTAG
EMI4183MTTAG